Am29F200B Known Good Wafer

Data Sheet



July 2003

The following document specifies Spansion memory products that are now offered by both Advanced Micro Devices and Fujitsu. Although the document is marked with the name of the company that originally developed the specification, these products will be offered to customers of both AMD and Fujitsu.

Continuity of Specifications

There is no change to this datasheet as a result of offering the device as a Spansion product. Any changes that have been made are the result of normal datasheet improvement and are noted in the document revision summary, where supported. Future routine revisions will occur when appropriate, and changes will be noted in a revision summary.

Continuity of Ordering Part Numbers

AMD and Fujitsu continue to support existing part numbers beginning with "Am" and "MBM". To order these products, please use only the Ordering Part Numbers listed in this document.

For More Information

Please contact your local AMD or Fujitsu sales office for additional information about Spansion memory solutions.







Am29F200B Known Good Wafer

2 Megabit (256 K x 8-Bit/128 K x 16-Bit)

CMOS 5.0 Volt-only, Boot Sector Flash Memory, Die Revision 1

Note: This supplement contains information on the Am29F200B in Known Good Wafer form. Refer to the Am29F200B standard datasheet (publication 21526) for full electrical specifications.

DISTINCTIVE CHARACTERISTICS

- Top or bottom boot block configurations available
- Minimum 1,000,000 write cycle guarantee per sector
- 20-year data retention at 125°C
- Tested to datasheet specifications at temperature

- Quality and reliability levels equivalent to standard packaged components
- Complies with JEDEC standards for wafer shipments

GENERAL DESCRIPTION

The Am29F200B in Known Good Wafer (KGW) form is an 2 Mbit, 5.0 volt-only Flash memory. AMD defines KGW as standard product in wafer form, tested for functionality and speed. AMD KGW products have the same reliability and quality as AMD products in packaged form.

Electrical Specifications

Refer to the Am29F200B data sheet, publication number 21526, for full electrical specifications on the Am29F200B in KGW form.

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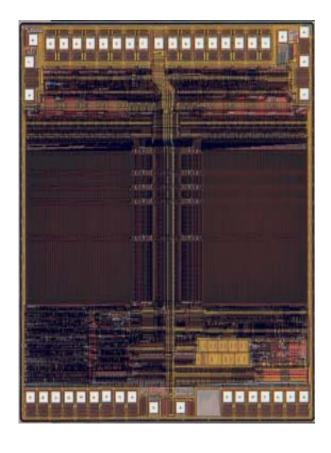


PRODUCT SELECTOR GUIDE

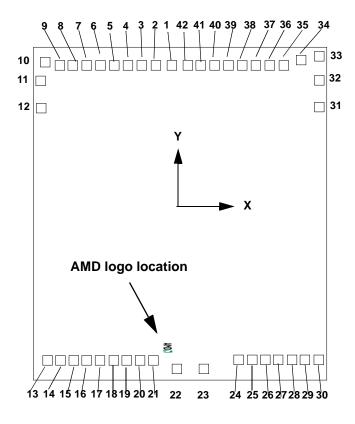
Family Part Number	Am29F200B KGW			
Speed Option ($V_{CC} = 5.0 \text{ V} \pm 10\%$)	-55 (V _{CC} = 5.0 V ± 5%)	-75 (V _{CC} = 5.0 V ± 5%)	-90	-120
Max access time, ns (t _{ACC})	55	70	90	120
Max CE# access time, ns (t _{CE})	55	70	90	120
Max OE# access time, ns (t _{OE})	30	30	35	50

Note: Refer to "Test Conditions" for additional information related to speed options.

DIE PHOTOGRAPH



DIE PAD LOCATIONS





PAD DESCRIPTION

Pad locations relative to $V_{\mbox{\footnotesize CC}}$.

Pad	Signal	Pad Ce	nter (mils)	Pad Center (r	millimeters)
rau	Signal	Х	Y	Х	Υ
1	V _{CC}	0.00	0.00	0.0000	0.0000
2	DQ4	-6.80	0.00	-0.1727	0.0000
3	DQ12	-12.80	0.00	-0.3251	0.0000
4	DQ5	-18.60	0.00	-0.4724	0.0000
5	DQ13	-24.50	0.00	-0.6223	0.0000
6	DQ6	-30.30	0.00	-0.7696	0.0000
7	DQ14	-36.30	0.00	-0.9220	0.0000
8	DQ7	-42.10	0.00	-1.0693	0.0000
9	DQ15/A-1	-48.00	0.00	-1.2192	0.0000
10	V _{SS}	-55.70	1.40	-1.4148	0.0356
11	BYTE#	-57.50	-6.50	-1.4605	-0.1651
12	A16	-57.50	-18.00	-1.4605	-0.4572
13	A15	-57.10	-124.90	-1.4503	-3.1725
14	A14	-51.30	-124.90	-1.3030	-3.1725
15	A13	-45.90	-124.90	-1.1659	-3.1725
16	A12	-40.00	-124.90	-1.0160	-3.1725
17	A11	-34.60	-124.90	-0.8788	-3.1725
18	A10	-28.80	-124.90	-0.7315	-3.1725
19	A9	-23.30	-124.60	-0.5918	-3.1648
20	A8	-17.40	-124.90	-0.4420	-3.1725
21	WE#	-12.00	-124.90	-0.3048	-3.1725
22	RESET#	-2.40	-128.60	-0.0610	-3.2664
23	RY/BY#	9.50	-128.60	0.2413	-3.2664
24	A7	30.30	-124.90	0.7696	-3.1725
25	A6	35.80	-124.90	0.9093	-3.1725
26	A5	41.60	-124.90	1.0566	-3.1725
27	A4	47.00	-124.90	1.1938	-3.1725
28	A3	52.90	-124.90	1.3437	-3.1725
29	A2	58.30	-124.90	1.4808	-3.1725
30	A1	64.10	-124.90	1.6281	-3.1725
31	A0	64.50	-18.00	1.6383	-0.4572
32	CE#	64.50	-6.50	1.6383	-0.1651
33	V _{SS}	64.50	3.80	1.6383	0.0965
34	OE#	55.00	2.30	1.3970	0.0584
35	DQ0	47.40	0.00	1.2040	0.0000
36	DQ8	41.50	0.00	1.0541	0.0000
37	DQ1	35.60	0.00	0.9042	0.0000
38	DQ9	29.70	0.00	0.7544	0.0000
39	DQ2	23.90	0.00	0.6071	0.0000
40	DQ10	18.00	0.00	0.4572	0.0000
41	DQ3	12.10	0.00	0.3073	0.0000
42	DQ11	6.20	0.00	0.1575	0.0000

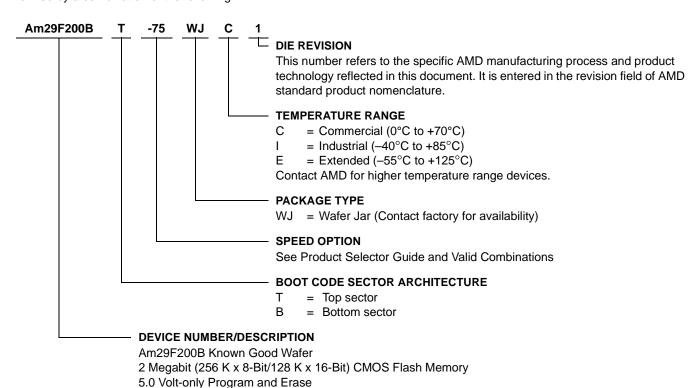
Note: The coordinates above are relative to the die center and can be used to operate wire bonding equipment.



ORDERING INFORMATION

Standard Products

AMD standard products are available in several packages and operating ranges. The order number (Valid Combination) is formed by a combination of the following:

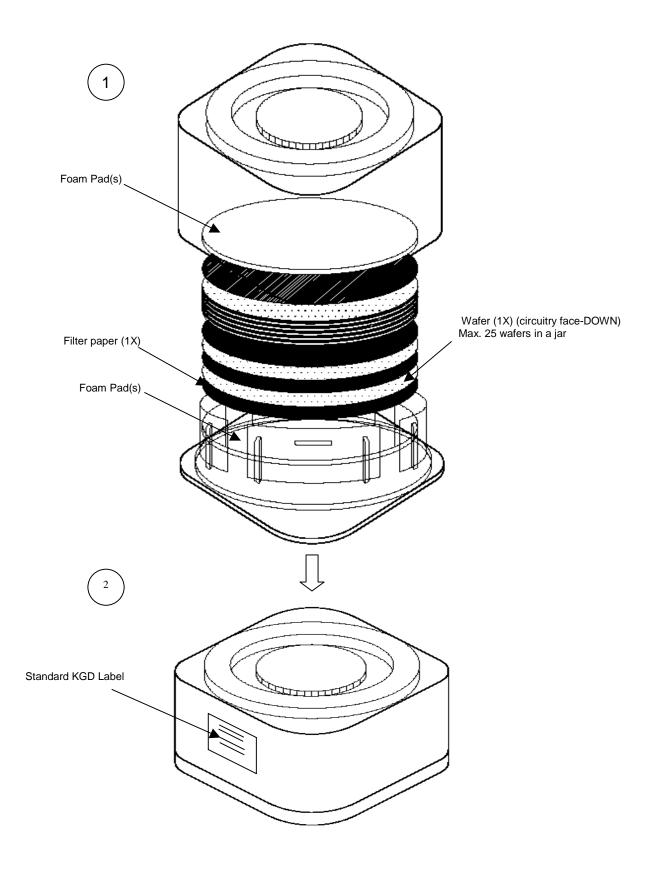


Valid Combinations			
AM29F200BT-55, AM29F200BB-55 (55 ns, V _{CC} = 5.0 V ±5%)			
AM29F200BT-75, AM29F200BB-75 (70 ns, V _{CC} = 5.0 V ±5%)	WJC1, WJI1, WJE1		
AM29F200BT-90, AM29F200BB-90			
AM29F200BT-120, AM29F200BB-120			

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations and to check on newly released combinations.

WAFER JAR DIAGRAM





PRODUCT TEST FLOW

Figure 1 provides an overview of AMD's Known Good Wafer test flow. For more detailed information, refer to the Am29F200B product qualification database. AMD implements quality assurance procedures throughout the product test flow. These QA procedures also allow

AMD to produce KGW products without requiring or implementing burn-in. In addition, an off-line qualification maintenance program (QMP) guarantees AMD quality standards are met on Known Good Wafer products.

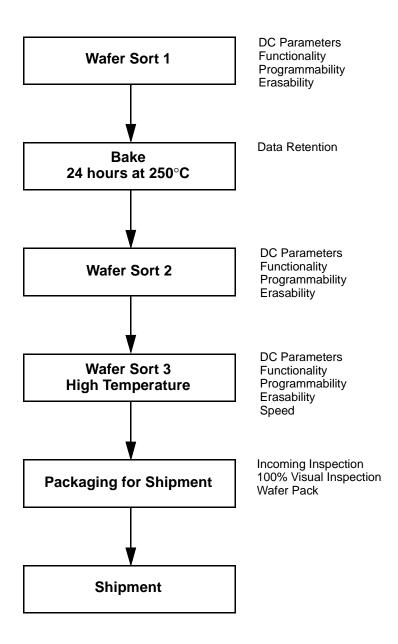


Figure 1. AMD KGW Product Test Flow

PHYSICAL SPECIFICATIONS

Wafer Size
Active Die $x = 3328.8 \mu m$; $y = 3594.8 \mu m$
x = 131 mils; y = 141.5 mils
Scribe width $x = 91.2 \mu m$; $y = 225.2 \mu m$
x = 3.59 mils; y = 8.87 mils
Step x = 3.42 mm; y = 3.82 mm
x = 134.6 mils; y = 150.4 mils
Wafer Thickness
Bond Pad Size 3.74 mils x 3.74 mils
95 μm x 95 μm
Minimum pad pitch137.8 μm
5.42 mils
Pad Area Free of Passivation
Pads Per Die
Bond Pad Metalization Al/Cu Minimum thickness: 10500 Å
Die Backside No metal,
may be grounded with Back-grind type finish (optional)
PassivationNitride/SOG/Nitride
Minimum thickness: 14700 Å
Ink dot height
20.3 µm max
Ink dot diameter
381 μm min
Edge die Inked Yes
DC OPERATING CONDITIONS
V _{CC} (Supply Voltage) 4.5 V to 5.5 V
Junction Temperature Under Bias:
Commercial, Industrial, and
Extended Temperature Range T _I (max) = 130°C

MANUFACTURING INFORMATION

Manufacturing		FASL
Test		. Penang, Malaysia
Manufacturing ID (Top Boot)	98480AK
	(Bottom Boot)	
Preparation for Sh	ipment	. Penang, Malaysia
Fabrication Proces	ss	CS39S
Die Revision		1

SPECIAL HANDLING INSTRUCTIONS

Processing

Do not expose KGW products to ultraviolet light or process them at temperatures greater than 250°C. Failure to adhere to these handling instructions will result in irreparable damage to the devices. For best yield, AMD recommends assembly in a Class 10K clean room with 30% to 60% relative humidity.

Storage

Store at a maximum temperature of 30°C in a nitrogenpurged cabinet or vacuum-sealed bag. Observe all standard ESD handling procedures.

TCC (Gappi) Tellago) TTTTTTTTTTTTTTTTTTTTTTTTTTTTTTTTTTTT
Junction Temperature Under Bias:
Commercial, Industrial, and
Extended Temperature Range T _J (max) = 130°C
Operating Temperature
Commercial 0°C to +70°C
Industrial
Extended
Contact AMD for higher temperature range devices.

TERMS AND CONDITIONS OF SALE FOR AMD NON-VOLATILE MEMORY DIE

All transactions relating to unpackaged die or unpackaged wafer(s) under this agreement shall be subject to AMD's standard terms and conditions of sale, or any revisions thereof, which revisions AMD reserves the right to make at any time and from time to time. In the event of conflict between the provisions of AMD's standard terms and conditions of sale and this agreement, the terms of this agreement shall be controlling.

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Initial release.

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